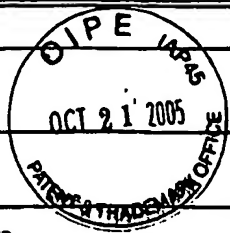


Sheet 1 of 1		INFORMATION DISCLOSURE STATEMENT						
FORM PTO 1449 (modified) U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE LIST OF REFERENCES CITED BY APPLICANT(S) <i>(Use several sheets if necessary)</i> Date Submitted to PTO: October 21, 2005			ATTY DOCKET NO. 2003_0966A		SERIAL NO. 10/619,006			
			APPLICANT Keishi KUBO et al.					
			FILING DATE July 15, 2003		GROUP 2877			
U.S. PATENT DOCUMENTS								
*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE	
	AA							
	AB							
	AC							
	AD							
	AE							
	AF							
	AG							
	AH							
	AI							
FOREIGN PATENT DOCUMENTS								
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO	
<i>RW</i>	AJ	11-201747	7/1999	JP			Abstract	
<i>P</i>	AK	11-195054	7/1999	JP			Abstract	
	AL							
	AM							
	AN							
OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)								
	AO							
	AP							
	AQ							
EXAMINER <i>RWADA</i>		DATE CONSIDERED <i>31 Oct 2005</i>						

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of form with next communication to applicant.

FORM PYG 1449 (modified)

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICELIST OF REFERENCES CITED BY APPLICANT(S)
(Use several sheets if necessary)

Date Submitted to PTO: November 10, 2003

ATTY DOCKET NO.
2003-0966ASERIAL NO.
10/619,006APPLICANT
Keishi KUBO et al.FILING DATE
July 15, 2003GROUP
2877

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
Rm	AA	6,480,286	11/2002	Kubo et al.			
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO	
	AJ							
	AK							
	AL							
	AM							
	AN							

OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)

m	AO	SEMI M1-0701 ^E "Specification for Polished Monocrystalline Silicon Wafers", SEMI M1-0701 ^E © SEMI 1978, 2001, pages 1- 26.
m	AP	SEMI M1.15-1000 "Standard for 300mm Polished Monocrystalline Silicon Wafers (Notched)", pages 1-3, SEMI M1.15-1000 © SEMI 1978, 2001.
	AQ	
EXAMINER	DATE CONSIDERED 25 Oct 2003	

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.